

<b>Notice of References Cited</b>	Application/Control No. 10/785,423	Applicant(s)/Patent Under Reexamination FLECK ET AL.	
	Examiner Janelle N. Young	Art Unit 2618	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0023152	02-2002	Oguchi, Naoki	709/223
*	B	US-2004/0114575	06-2004	Morita et al.	370/352
*	C	US-6,891,797	05-2005	Frouin, Laurent	370/230
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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